

Search Notes

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Chuck Huynh

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Reexamination

LEE ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
455	414.1	7/27/2006	CH

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STIC for Korean Patent and Translation	7/27/2006	CH
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